

# EPI - Wafer

## AlN



**Feature** AlN Epi. Wafer  
Single side polished (Growth surface)

**Diameter** 2" (50.8mm)

**Thickness (Included substrate)** 430 $\mu\text{m}$  $\pm$ 15 $\mu\text{m}$

**Structure** AlN / Sapphire substrate



AlN on Sapphire Wafer

### Characteristics (at 25°C)

Parameter		Typ.	Test Conditions
Crack Free AlN Surface Area	Diameter	>44mm	-
	Thickness	<3 $\mu\text{m}$	
XRD	(002)	<250 arcsec	PANalytical 社 HR-XRD Rocking curves FWHMs
	(102)	<400 arcsec	
RMS	5 $\mu\text{m}$ * 5 $\mu\text{m}$	<1 nm	AFM

